

<b>INFORMATION DISCLOSURE CITATION</b> PTO-1449		Customer Number <b>26615</b>	ATTORNEY'S Dkt No. <b>H1491</b>	APPLICATION NO. <b>Unassigned 10,653,234</b>		
			APPLICANT(S) <b>Bin Yu et al.</b>			
			FILING DATE <b>September 3, 2003</b>	GROUP <b>Unassigned 2818</b>		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
<i>dha</i>	Digh Hisamoto et al.: "FinFET - A Self-Aligned Double-Gate MOSFET Scalable to 20 nm," IEEE Transactions on Electron Devices, Vol. 47, No. 12, December 2000, pages 2320-2325.					
<i>dha</i>	Yang-Kyu Choi et al.: "Sub-20nm CMOS Fin FET Technologies," 2001 IEEE, IEDM, pages 421-424.					
<i>dha</i>	Xuejue Huang et al.: "Sub-50 nm P-Channel Fin FET," IEEE Transactions on Electron Devices, Vol. 48, No. 5, May 2001, pages 880-886.					
<i>dha</i>	Yang-Kyu Choi et al.: "Nanoscale CMOS Spacer FinFET for the Terabit Era," IEEE Electron Device Letters, Vol. 23, No. 1, January 2002, pages 25-27.					
<i>dha</i>	Xuejue Huang et al.: "Sub 50-nm FinFET: PMOS," 1999 IEEE, IEDM, pages 67-70.					
<i>dha</i>	Co-pending U.S. Patent Application Serial No. 10/632,965, filed August 4, 2003, entitled: "Semiconductor Device Having A Thin Fin And Raised Source/Drain Areas," Haihong Wang et al.; 18 page specification and 19 sheets of drawings.					
EXAMINER	<i>Thao</i>			DATE CONSIDERED <i>03/22/05</i>		

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